

"Production of negative ions in an helicon hydrogen plasma in front of a HOPG sample"



"Role of double capture and sputtering"

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Summary

Motivation

Experimental set-up « PHISIS »

IDF measurement

H- production (Volume and surface)

H- produced at surface

Energy deposit and isotopic effect

Sample temperature measurements

Coverage, sputtering and double capture

Temporal behaviour

Conclusion

Motivation

- Improve neutral beam injection (ITER)
- Negative ion production (thruster)
- Stability of plasma source
- Dust chemistry (sheath behavior)
- Improvement? of H- production with a small additional argon (10%)



Plasma Helicon to Irradiate Surface In-Situ



« PHISIS »







The langmuir probe







Sketch of our setup negative ion detection





H- IDF (surface and volume)

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H- IEDF





IDF of negative ions (surface) 6x10³ 2.0x10⁴ 0.4 Pa H₂, 100W V_= 47V 0.4 Pa H₂, 100W 5x10³ V_= -60V V = 47V 1.6x10^⁴ V = 0V 4x10 H⁻ (arb.u.) 1.2x10⁴ H[¯] (arb.u.) 3x10 $V_p - V_s$ 8.0x10³ 2x10 $V_p - V_s$ 1x10³ 4.0x10³ 0 100 110 120 130 70 60 90 150 160 80 140 0.0 50 60 70

80

90

0

10

20

30

40

Potentiel (V)

Energie des ions H (eV)





H- (Ar-H2)versus ion energy



H- versus incoming proton



Sample temperature behavior









Sputtering component of Hsurface production



Temporal behavior



Temporal behavior







Conclusion



IDF show volume and surface contributions H- Behaviour with energy of incoming ions H- Behaviour versus temperature shows Double electron and sputtering components Temporal study clearly show a contribution of coverage? Theory of sputtering with defects and dangling bonds? Implantation of ions at low energy? Electron capture? Stability of the sheath (width of the peak)? Arches 2008 Marseille

